Power MOSFET

Complementary, 20 V, +3.1 A / -2.1 A, ChipFET $^{\text{\tiny TM}}$

Features

- Complementary N Channel and P Channel MOSFET
- Small Size, 40% Smaller than TSOP-6 Package
- Leadless SMD package Featuring Complementary Pair
- ChipFET Package Provides Great Thermal Characteristics Similar to Larger Packages
- Low R_{DS(on)} in a ChipFET Package for High Efficiency Performance
- Low Profile (< 1.10 mm) Allows Placement in Extremely Thin Environments Such as Portable Electronics

Applications

- Load Switch Applications Requiring Level Shift
- DC-to-DC Conversion Circuits
- Drive Small Brushless DC Motors
- Designed for Power Management Applications in Portable, Battery Powered Products

MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

Parame	Symbol	Value	Unit		
Drain-to-Source Voltage	V_{DSS}	20	V		
Gate-to-Source Voltage	V_{GS}	±12	V		
Continuous Drain Current (Note 1)				3.1	Α
Current (Note 1)	Steady State	T _A = 85°C		2.15	
	P-Ch Steady			-2.1	
	State	$T_A = 85^{\circ}C$		-1.5	
		t = 10 μs	I _{DM}	10	Α
(Note 1)	P-Ch	t = 10 μs		-7.0	
Power Dissipation –Stead (Note 1)	P _D	1.1	W		
Operating Junction and St Temperature	T _J , T _{STG}	–55 to 150	°C		
Lead Temperature for Solo (1/8" from case for 10 second	TL	260	°C		

THERMAL RESISTANCE RATINGS

Parameter	Symbol	Max	Unit	
Junction-to-Ambient Steady-State (Note 1)	$R_{\theta JA}$	110	°C/W	

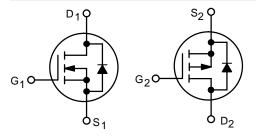
 Surface-mounted on FR4 board using 1 in sq. pad size (Cu area = 1.127 in sq. [1 oz] including traces).



ON Semiconductor®

http://onsemi.com

V _{(BR)DSS}	R _{DS(on)} TYP	I _D MAX
N-Channel	60 mΩ @ 4.5 V	3.1 A
20 V	80 mΩ @ 2.5 V	
P-Channel	130 mΩ @ -4.5 V	–2.1 A
–20 V	200 mΩ @ -2.5 V	-2.1 A

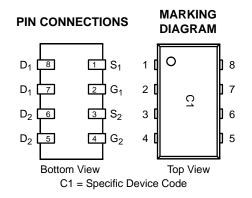


N-Channel MOSFET

P-Channel MOSFET



ChipFET CASE 1206A STYLE 2



ORDERING INFORMATION

Device	Package	Shipping
NTHC5513T1	ChipFET	3000/Tape & Reel
NTHC5513T1G	ChipFET (Pb-Free)	3000/Tape & Reel

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise noted)

Parameter	Symbol	N/P	Test Conditions		Min	Тур	Max	Unit
OFF CHARACTERISTICS (Note 2)		-			-	-	-	-
Drain-to-Source Breakdown Voltage	n–to–Source Breakdown Voltage $V_{(BR)DSS}$ N $I_D = 250$		I _D = 250 μA	20			V	
		Р	$V_{GS} = 0 V$	I _D = -250 μA	-20			
Zero Gate Voltage Drain Current	I _{DSS}	N	$V_{GS} = 0 \text{ V}, V_{DS} =$	= 16 V			1.0	μΑ
		Р	$V_{GS} = 0 \text{ V}, V_{DS} =$	-16 V			-1.0	
		N	V _{GS} = 0 V, V _{DS} = 16 V	, T _J = 85 °C			5	
		Р	$V_{GS} = 0 \text{ V}, V_{DS} = -16 \text{ V}$	/, T _J = 85 °C			-5	
Gate-to-Source Leakage Current	I _{GSS}		$V_{DS} = 0 V, V_{GS} =$	= ±12 V			±100	nA
ON CHARACTERISTICS (Note 2)	•				•	•		
Gate Threshold Voltage	V _{GS(TH)}	N		I _D = 250 μA	0.6		1.2	V
		Р	$V_{GS} = V_{DS}$	I _D = -250 μA	-0.6		-1.2	
Drain-to-Source On Resistance	R _{DS} (on)	N	V _{GS} = 4.5 V , I _D =	= 3.1 A		0.058	0.080	
		Р	$V_{GS} = -4.5 \text{ V}, I_{D} =$	= –2.1 A		0.130	0.155	
		N	$V_{GS} = 2.5 \text{ V}, I_D = 2.3 \text{ A}$ $V_{GS} = -2.5 \text{ V}, I_D = -1.7 \text{ A}$			0.077	0.115	Ω
		Р				0.200	0.240	
Forward Transconductance	9FS	N	$V_{DS} = 10 \text{ V}, I_D = 3.0 \text{ A}$ $V_{DS} = -10 \text{ V}, I_D = -2.1 \text{ A}$			6.0		S
		Р				6.0		
CHARGES AND CAPACITANCES	<u>-</u>		-		-	-		
Input Capacitance	C _{ISS}	N	V _{DS} = 10 V			180		pF
		Р		V _{DS} = -10 V		185		
Output Capacitance	C _{OSS}	N	4 4 MILL V 0 V	V _{DS} = 10 V		80		
		Р	$f = 1 \text{ MHz}, V_{GS} = 0 \text{ V}$	V _{DS} = -10 V		95		
Reverse Transfer Capacitance	C _{RSS}	N		V _{DS} = 10 V		25		
		Р	V _{DS} = -			30		
Total Gate Charge	Q _{G(TOT)}	N	V _{GS} = 4.5 V, V _{DS} = 10 V, I _D = 3.1 A			2.6	4.0	nC
		Р	$V_{GS} = -4.5 \text{ V}, V_{DS} = -10 \text{ V}, I_D = -2.1 \text{ A}$			3.0	6.0	
Gate-to-Source Gate Charge	Q_{GS}	N	V _{GS} = 4.5 V, V _{DS} = 10 V, I _D = 3.1 A			0.6		
		Р	$V_{GS} = -4.5 \text{ V}, V_{DS} = -10 \text{ V}, I_D = -2.1 \text{ A}$			0.5		
Gate-to-Drain "Miller" Charge	Q_{GD}	N	$V_{GS} = 4.5 \text{ V}, V_{DS} = 10 \text{ V}, I_D = 3.1 \text{ A}$			0.7		
		Р	$V_{GS} = -4.5 \text{ V}, V_{DS} = -10 \text{ V}, I_D = -2.1 \text{ A}$			0.9		

NOTES:

- Pulse Test: pulse width ≤ 250 μs, duty cycle ≤ 2%.
 Switching characteristics are independent of operating junction temperatures.

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise noted)

Parameter	Symbol	N/P	Test Conditions		Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS (No	ote 3)							
Turn-On Delay Time	t _{d(ON)}					5.0	10	ns
Rise Time	t _r	N	$V_{DD} = 16 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 3.1 \text{ A},$			9.0	18	
Turn-Off Delay Time	t _{d(OFF)}		$R_G = 2.5 \Omega$	2		10	20	
Fall Time	t _f					3.0	6.0	
Turn-On Delay Time	t _{d(ON)}		V_{DD} = -16 V, V_{GS} = -4.5 V, I_{D} = -2.1 A, R_{G} = 2.5 Ω			7.0	12	
Rise Time	t _r	P				13	25	
Turn-Off Delay Time	t _{d(OFF)}					33	50	
Fall Time	t _f					27	40	
DRAIN-SOURCE DIODE CHARACTE	RISTICS							
Forward Diode Voltage (Note 2)5	V_{SD}	N	V0.V	I _S = 3.1 A		0.8	1.15	V
		Р	$V_{GS} = 0 V$	I _S = -2.1 A		-0.8	-1.15	
Reverse Recovery Time (Note 3)	t _{RR}	N	I _S = 1.5 A	I _S = 1.5 A		12.5		ns
		Р	I _S = −1.5 A			32		
Charge Time	ta	N	$I_{S} = 1.5 \text{ A}$ $I_{S} = -1.5 \text{ A}$			9.0		
		Р				10		
Discharge Time	t _b	N	-II / -It 400 A / -	I _S = 1.5 A		3.5		
		Р		I _S = -1.5 A		22		
Reverse Recovery Charge	Q_{RR}	N		I _S = 1.5 A		6.0		nC
		Р		I _S = −1.5 A		15		

NOTES:

- 2. Pulse Test: pulse width \leq 250 μ s, duty cycle \leq 2%. 3. Switching characteristics are independent of operating junction temperatures.

TYPICAL N-CHANNEL PERFORMANCE CURVES

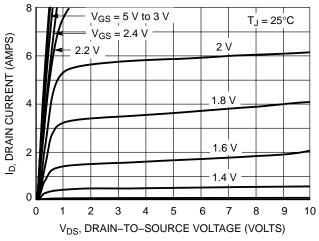


Figure 1. On-Region Characteristics

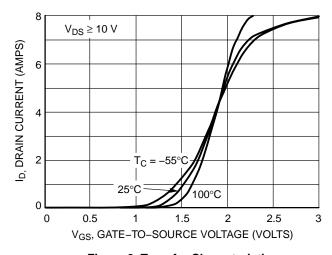


Figure 2. Transfer Characteristics

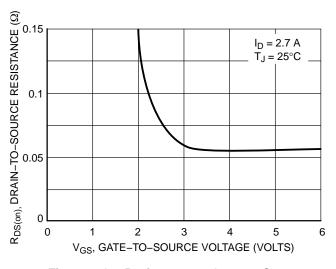


Figure 3. On-Resistance vs. Gate-to-Source Voltage

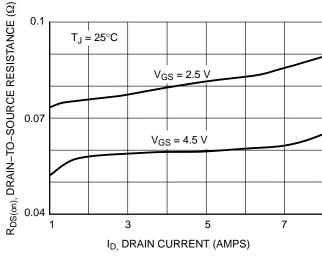


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

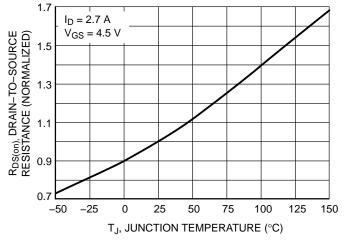


Figure 5. On–Resistance Variation with Temperature

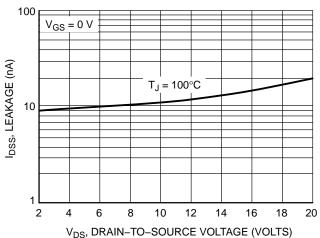
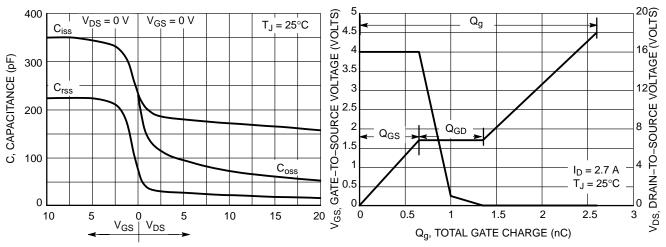


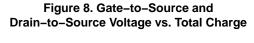
Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL N-CHANNEL PERFORMANCE CURVES



GATE-TO-SOURCE OR DRAIN-TO-SOURCE VOLTAGE (VOLTS)

Figure 7. Capacitance Variation



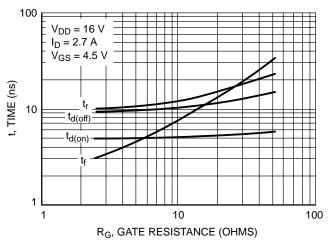


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

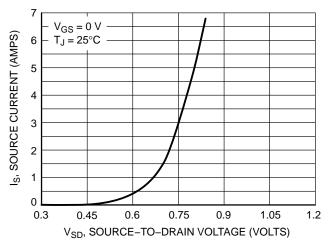


Figure 10. Diode Forward Voltage vs. Current

TYPICAL P-CHANNEL PERFORMANCE CURVES

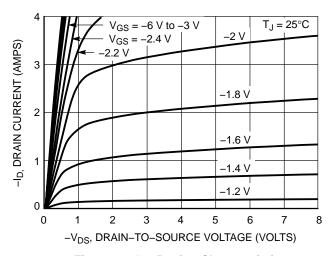


Figure 11. On-Region Characteristics

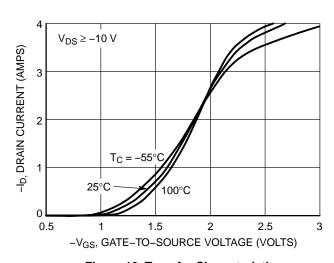


Figure 12. Transfer Characteristics

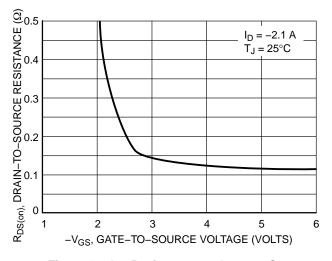


Figure 13. On-Resistance vs. Gate-to-Source Voltage

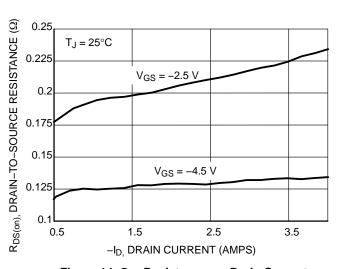


Figure 14. On–Resistance vs. Drain Current and Gate Voltage

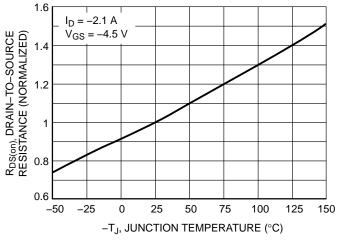


Figure 15. On–Resistance Variation with Temperature

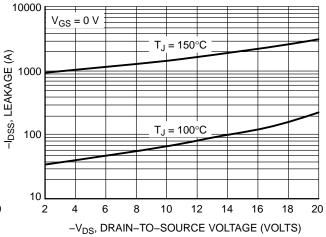


Figure 16. Drain-to-Source Leakage Current vs. Voltage

TYPICAL P-CHANNEL PERFORMANCE CURVES

(T_J = 25°C unless otherwise noted)

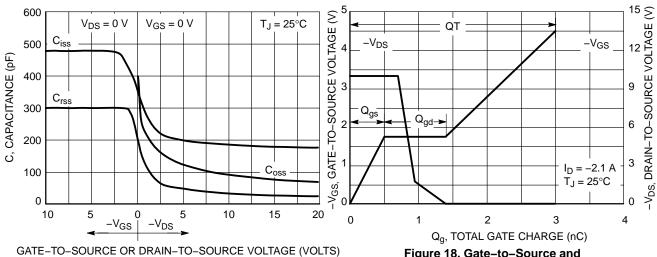


Figure 18. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

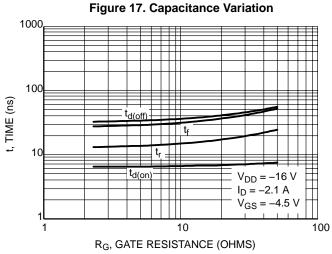


Figure 19. Resistive Switching Time Variation vs. Gate Resistance

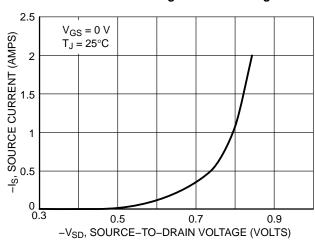


Figure 20. Diode Forward Voltage vs. Current

TYPICAL PERFORMANCE CURVES

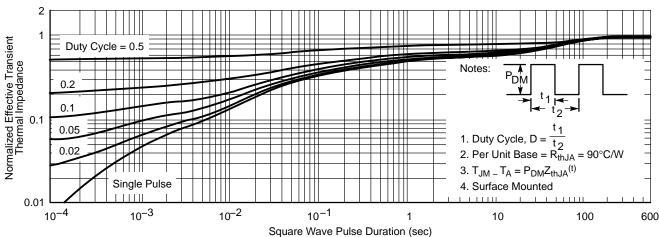
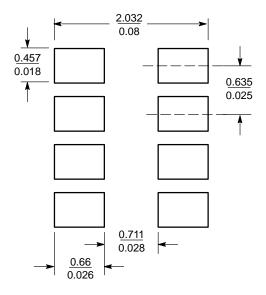


Figure 21. Thermal Response



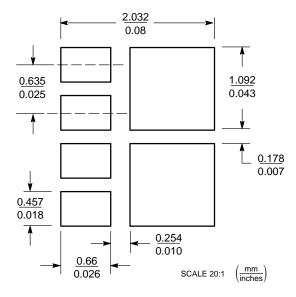


Figure 22. Basic

Figure 23. Style 2

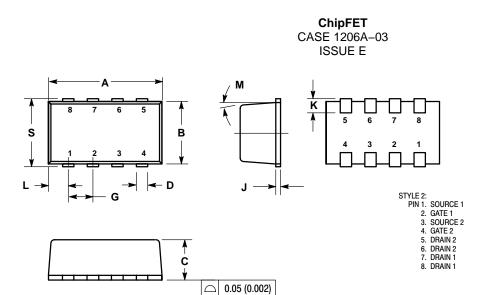
BASIC PAD PATTERNS

The basic pad layout with dimensions is shown in Figure 22. This is sufficient for low power dissipation MOSFET applications, but power semiconductor performance requires a greater copper pad area, particularly for the drain leads.

The minimum recommended pad pattern shown in Figure 23 improves the thermal area of the drain connections (pins 5, 6, 7, 8) while remaining within the

confines of the basic footprint. The drain copper area is 0.0019 sq. in. (or 1.22 sq. mm). This will assist the power dissipation path away from the device (through the copper lead–frame) and into the board and exterior chassis (if applicable) for the single device. The addition of a further copper area and/or the addition of vias to other board layers will enhance the performance still further.

PACKAGE DIMENSIONS



- NOTES:
 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
 2. CONTROLLING DIMENSION: MILLIMETER.
 3. MOLD GATE BURRS SHALL NOT EXCEED 0.13 MM PER SIDE.
 4. LEADFRAME TO MOLDED BODY OFFSET IN HORIZONTAL AND VERTICAL SHALL NOT EXCEED 0.08 MM.
 5. DIMENSIONS A AND B EXCLUSIVE OF MOLD GATE BURRS.
 6. NO MOLD FLASH ALLOWED ON THE TOP AND BOTTOM LEAD SURFACE.
 7. 1206A-01 AND 1206A-02 OBSOLETE. NEW STANDARD IS 1206A-03.

	MILLIN	IETERS	INCHES		
DIM	MIN	MAX	MIN	MAX	
Α	2.95	3.10	0.116	0.122	
В	1.55	1.70	0.061	0.067	
С	1.00	1.10	0.039	0.043	
D	0.25	0.35	0.010	0.014	
G	0.65	BSC	0.025 BSC		
J	0.10	0.20	0.004	0.008	
K	0.28	0.42	0.011	0.017	
L	0.55	BSC	0.022 BSC		
M	5 °	NOM	5°	NOM	
S	1.80	2.00	0.072	0.080	

ChipFET is a trademark of Vishay Siliconix.

ON Semiconductor and was are registered trademarks of Semiconductor Components Industries, LLC (SCILLC). SCILLC reserves the right to make changes without further notice to any products herein. SCILLC makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does SCILLC assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. "Typical" parameters which may be provided in SCILLC data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. SCILLC does not convey any license under its patent rights nor the rights of others. SCILLC products are not designed, intended, or authorized for use as components in systems intended for surgical implant into the body, or other applications intended to support or sustain life, or for any other application in which the failure of the SCILLC product could create a situation where personal injury or death may occur. Should Buyer purchase or use SCILLC products for any such unintended or unauthorized application, Buyer shall indemnify and hold SCILLC and its officers, employees, subsidiaries, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that SCILLC was negligent regarding the design or manufacture of the part. SCILLC is an Equal Opportunity/Affirmative Action Employer. This literature is subject to all applicable copyright laws and is not for resale in any manner.

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor P.O. Box 5163, Denver, Colorado 80217 USA Phone: 303-675-2175 or 800-344-3860 Toll Free USA/Canada Fax: 303-675-2176 or 800-344-3867 Toll Free USA/Canada

Email: orderlit@onsemi.com

N. American Technical Support: 800-282-9855 Toll Free

Japan: ON Semiconductor, Japan Customer Focus Center 2-9-1 Kamimeguro, Meguro-ku, Tokyo, Japan 153-0051 Phone: 81-3-5773-3850

ON Semiconductor Website: http://onsemi.com

Order Literature: http://www.onsemi.com/litorder

For additional information, please contact your local Sales Representative.